

Please add the following new claims:

17. (New) An apparatus according to claim 14, wherein measuring of the position of the reference point on the surface of the object table comprises directing a measurement beam to be incident on a diffraction grating, provided on the object table, substantially independent of the tilt of the object table and detecting the position of said diffraction grating.
18. (New) An apparatus according to claim 14, wherein measuring of the position of the reference point on the surface of the object table comprises directing a measurement beam along an incident path substantially perpendicular to a diffraction grating provided on the object table, and reflecting said measurement beam along a return path substantially parallel to the incident path and passing through said diffraction grating in a direction opposite to the incident path.
19. (New) An apparatus according to claim 15, wherein detecting displacements of the reference point of said object table comprises directing a measurement beam to be incident on a diffraction grating, provided on said object table, substantially independent of the tilt of said object table and detecting the position of said diffraction grating.
20. (New) An apparatus according to claim 15, wherein detecting displacements of the reference point of said object table comprises directing a measurement beam along an incident path substantially perpendicular to a diffraction grating provided on said object table, and reflecting said measurement beam along a return path substantially parallel to the incident path and passing through said diffraction grating in a direction opposite to the incident path.